

FDB8876

N-Channel PowerTrench® MOSFET

30V, **71A**, **8.5m**Ω

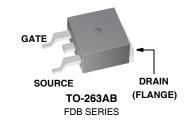
General Descriptions

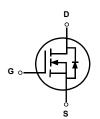
This N-Channel MOSFET has been designed specifically to improve the overall efficiency of DC/DC converters using either synchronous or conventional switching PWM controllers. It has been optimized for low gate charge, low $r_{DS(ON)}$ and fast switching speed.



Features

- $r_{DS(ON)} = 8.5 \text{m}\Omega$, $V_{GS} = 10 \text{V}$, $I_D = 40 \text{A}$
- $r_{DS(ON)}$ = 10.3mΩ, V_{GS} = 4.5V, I_D = 40A
- High performance trench technology for extremely low r_{DS(ON)}
- Low gate charge
- High power and current handling capability
- RoHS Compliant





MOSFET Maximum Ratings T_A = 25°C unless otherwise noted

Symbol	Parameter	Ratings	Units
V_{DSS}	Drain to Source Voltage	30	V
V_{GS}	Gate to Source Voltage	±20	V
	Drain Current		
	Continuous (T _C = 25°C, V _{GS} = 10V)	71	Α
ID	Continuous ($T_C = 25^{\circ}C$, $V_{GS} = 4.5V$)	65	Α
	Pulsed	Figure 4	Α
E _{AS}	Single Pulse Avalanche Energy (Note 1)	180	mJ
P_{D}	Power dissipation	70	W
T _J , T _{STG}	Operating and Storage Temperature	-55 to 175	°C

Thermal Characteristics

$R_{\theta JC}$	Thermal Resistance Junction to Case TO-263	2.14	°C/W
$R_{\theta JA}$	Thermal Resistance Junction to Ambient TO-263,1in ² copper pad area	43	°C/W

Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDB8876	FDB8876	TO-263AB	330mm	24mm	800 units

Electrical Characteristics T_A = 25°C unless otherwise noted

Symbol	Parameter	Test Conditions		Min	Тур	Max	Units
Off Characteristics							
B _{VDSS}	Drain to Source Breakdown Voltage	$I_D = 250 \mu A, V_{GS} = 0 V$		30	-	-	V
1	Zero Gate Voltage Drain Current	V _{DS} = 24V				1	μΑ
DSS	Zero Gate voltage Drain Current	$V_{GS} = 0V$ T_A	= 150°C	-	-	250	
I _{GSS}	Gate to Source Leakage Current	V _{GS} = ±20V		-	-	±100	nA

On Characteristics

V _{GS(TH)}	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, I_{D} = 250 \mu A$	1.2	-	2.5	V
	Drain to Source On Resistance	I _D = 40A, V _{GS} = 10V	-	5.7	8.5	
r		I _D = 40A, V _{GS} = 4.5V	-	7.3	10.3	mΩ
r _{DS(ON)}		I _D = 40, V _{GS} = 10V, T _A = 175°C	-	11	14	11122

Dynamic Characteristics

C _{ISS}	Input Capacitance	V _{DS} = 15V, V _{GS} = 0V, f = 1MHz		-	1700	-	pF
C _{OSS}	Output Capacitance			-	340	-	pF
C _{RSS}	Reverse Transfer Capacitance	1 1101112		-	220	-	pF
R_G	Gate Resistance	V _{GS} =0.5V, f = 1MHz		-	2.1	-	Ω
$Q_{g(TOT)}$	Total Gate Charge at 10V	V_{GS} = 0V to 10V	V _{DD} = 15V	-	32	45	nC
$Q_{g(5)}$	Total Gate Charge at 5V	V_{GS} = 0V to 5V	I _D = 40A	-	17	24	nC
$Q_{g(TH)}$	Threshold Gate Charge	V_{GS} = 0V to 1V	$I_g = 1.0 \text{mA}$	-	1.6	2.4	nC
Q_{gs}	Gate to Sourse Gate Charge			-	4.7	-	nC
Q _{gs2}	Gate Charge Threshold to Plateau			-	3.1	-	nC
Q _{gd}	Gate to Drain "Miller" Charge			-	6.8	-	nC

Switching Characteristics $(V_{GS} = 10V)$

t_{ON}	Turn-On Time		-	-	183	ns
t _{d(ON)}	Turn-On Delay Time		-	9	-	ns
t _r	Rise Time	V _{DD} = 15V, I _D = 40A	-	113	-	ns
t _{d(OFF)}	Turn-Off Delay Time	V_{GS} = 10V, R_{GS} = 10 Ω	-	50	-	ns
t _f	Fall Time		-	41	-	ns
t _{OFF}	Turn-Off Time		-	-	137	ns

Drain-Source Diode Characteristic

V _{SD} Source to Drain Diode Voltage	Course to Duein Diede Veltere	I _{SD} = 40A	-	-	1.25	V
	I _{SD} = 3.2A	-	-	1.0	V	
t _{rr}	Reverse Recovery Time	$I_{SD} = 40A$, $dI_{SD}/dt = 100A/\mu s$	-	-	22	ns
Q_{RR}	Reverse Recovered Charge	$I_{SD} = 40A, dI_{SD}/dt = 100A/\mu s$	-	-	8	nC

Notes:

1: Starting T_J =25 O C,L=1mH,I $_{AS}$ =19A,V $_{DD}$ =27V,V $_{GS}$ =10V



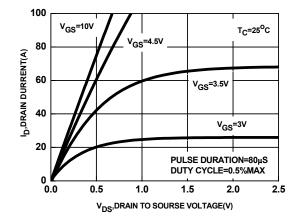


Figure 1. On Region Characteristics

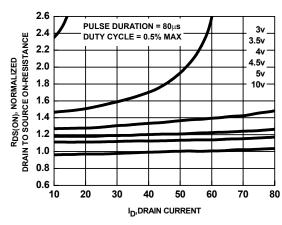


Figure 2. On-Resistance Variation with Drain Current and Gate Voltage

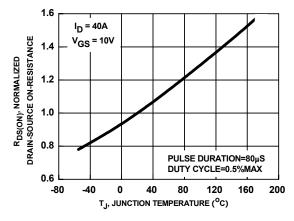


Figure 3. On Resistance Variation with Temperature

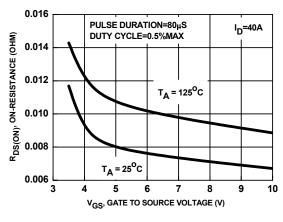


Figure 4. On-Resistance Variation with Gate-to-Source Votlage

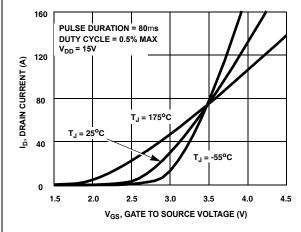


Figure 5. Transfer Characteristics

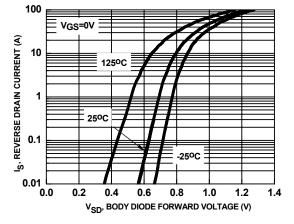


Figure 6. Body Diode Forward Voltage Variation With Source Current and Temperature



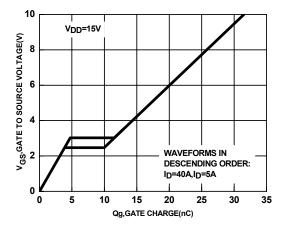


Figure 7. Gate Charge characteristics

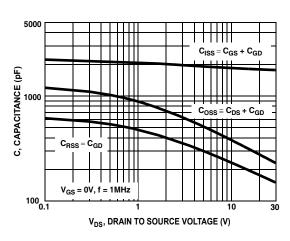


Figure 8. Saturation characteristics

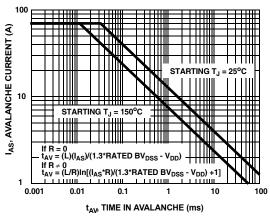


Figure 9. Unclamped Inductive Switching Capability

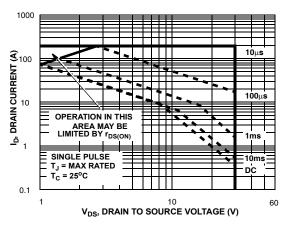


Figure 10. Safe Operating Area

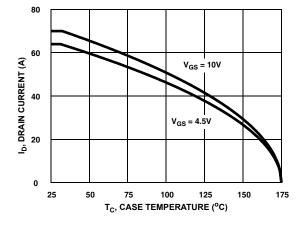


Figure 11. Maximum Continuous Drain Current vs Case Temperature

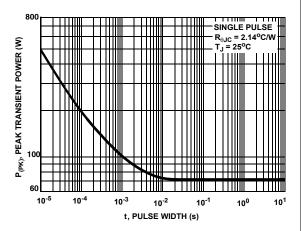


Figure 12. Normalized Drain to Source Breake Down Voltage vs Junction Temperature

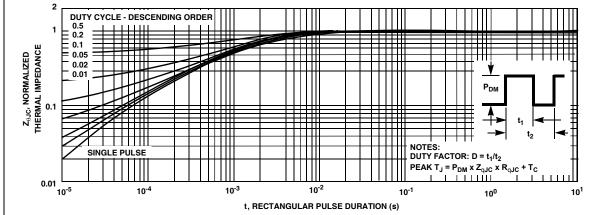


Figure 13. Normolized Maximum Transient Thermal Impedance

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